


Search Notes 	Application/Control No. 10520031	Applicant(s)/Patent Under Reexamination MARTON ET AL.
	Examiner Young J Kim	Art Unit 1637

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SEARCH NOTES		
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Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	8/26/2008	/YJK/
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Patent Database search updated - see enclosed for text-search strategy	2/3/2009	/YJK/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
	Interference search history - see print out	2/3/2009	/YJK/

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